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# MR45V200A

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2M(262,144-Word × 8-Bit) FeRAM (Ferroelectric Random Access Memory) SPI

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## GENERAL DESCRIPTION

The MR45V200A is a nonvolatile 262,144-word x 8-bit ferroelectric random access memory (FeRAM) developed in the ferroelectric process and silicon-gate CMOS technology. The MR45V200A is accessed using Serial Peripheral Interface. Unlike SRAMs, this device, whose cells are nonvolatile, eliminates battery backup required to hold data. This device has no mechanisms of erasing and programming memory cells and blocks, such as those used for various EEPROMs. Therefore, the write cycle time can be equal to the read cycle time and the power consumption during a write can be reduced significantly.

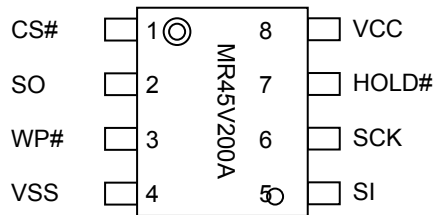
The MR45V200A can be used in various applications, because the device is guaranteed for the write/read tolerance of  $10^{12}$  cycles per bit and the rewrite count can be extended significantly.

## FEATURES

- 262,144-word × 8-bit configuration (Serial Peripheral Interface : SPI)
- A single 2.7V to 3.6V power supply
- Operating frequency: 34MHz
- Read/write tolerance:  $10^{12}$  cycles/bit
- Data retention: 10 years
- Guaranteed operating temperature range: -40 to 85°C (Extended temperature version)
- Package options:
  - 8-pin plastic DIP

**PIN CONFIGURATION**

8-pin plastic DIP



Note:

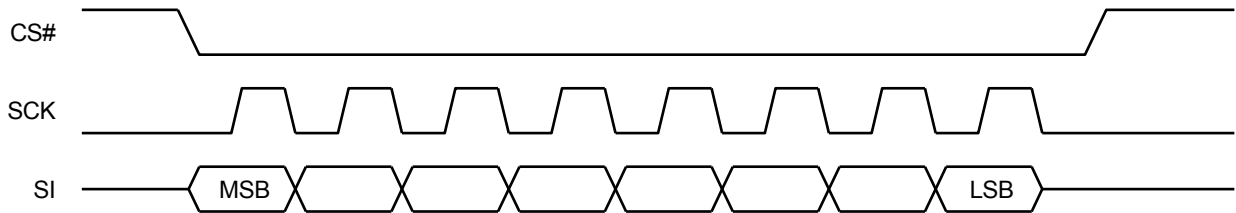
Signal names that end with # indicate that the signals are negative-true logic.

**PIN DESCRIPTIONS**

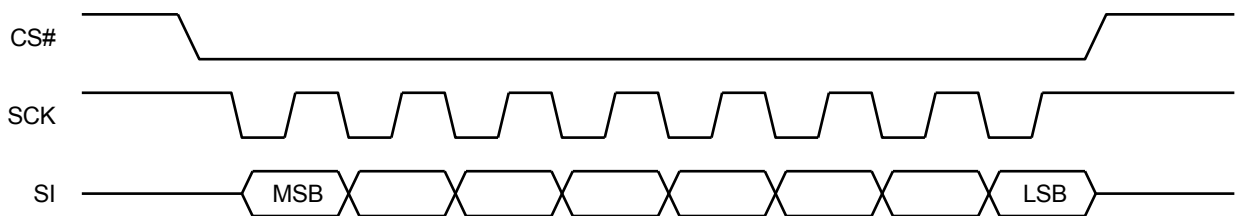
Pin Name	Description
CS#	Chip Select (input, negative logic) Latches an address by low input, activates the FeRAM, and enables a read or write operation.
WP#	Write Protect( input , negative logic ) Write Protect pin controls write-operation to the status-register(BP0,BP1). This pin should be fixed low or high in write-operations.
HOLD#	HOLD( input , negative logic ) Hold pin is used when the serial-communication suspended without disable the chip select. When HOLD# is low ,the serial-output is in High-Z status and serial-input/serial-clock are "Don't Care" . CS# should be low in hold operation.
SCK	Serial Clock Serial Clock is the clock input pin for setting for serial data timing. Inputs are latched on the rising edge and output occur on the falling edge.
SI	Serial input SI pins are serial input pins for Operation-code , addresses ,and data-inputs .
SO	Serial output SO pins are serial output pins.
V <sub>CC</sub> , V <sub>SS</sub>	Power supply Apply the specified voltage to V <sub>CC</sub> . Connect V <sub>SS</sub> to ground.

**SPI**

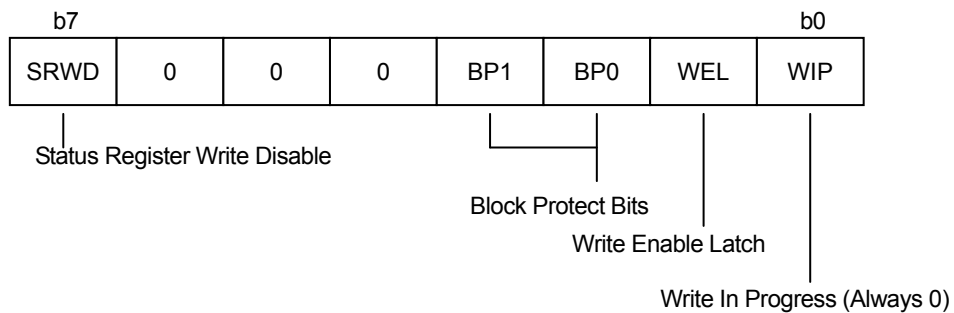
**SPI mode0 (CPOL=0, CPHA=0)**



**SPI mode3 (CPOL=1, CPHA=1)**



**Status Register**



Name	Function
WIP	Fixed to 0.
WEL	Write Enable Latch. This indicates internal WEL condition.
BP0,BP1	Block Protect :These bits can be changed protect area . This is the software protect.
SRWD	Status Register Write Disable ( SRWD ) : SRWD controls the effect of the hardware WP# pin. This device will be in hardware-protect by combination of SRWD and WP#.
0	Fixed to 0.

### Operation-Code

Operation codes are listed in the table below. If the device receives invalid operation code, the device will be deselected.

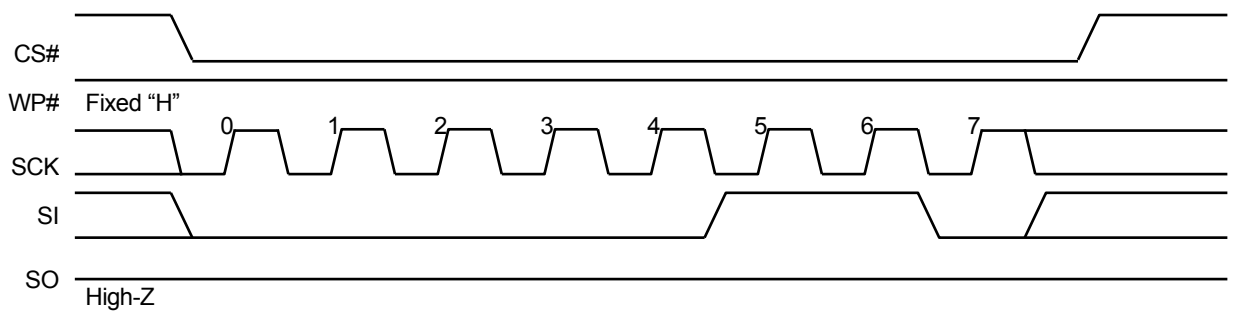
Instruction	Description	Instruction format
WREN	Write Enable	0000 0110
WRDI	Write Disable	0000 0100
RDSR	Read Status Register	0000 0101
WRSR	Write Status Register	0000 0001
READ	Read from Memory Array	0000 0011
WRITE	Write to Memory Array	0000 0010

### COMMANDS

#### WREN(Write Enable)

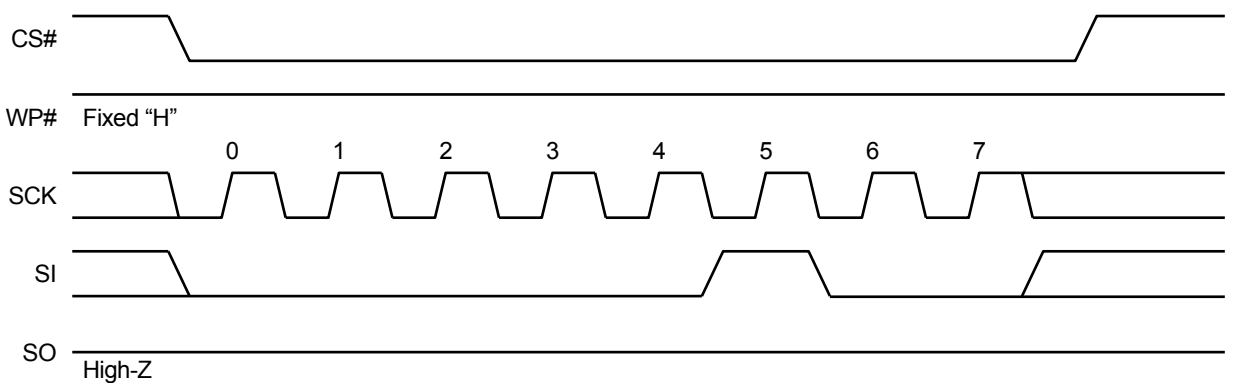
It is necessary to set Write Enable Latch (WEL) bit before write-operation (WRITE and WRSR).

WREN command sets WEL bit.



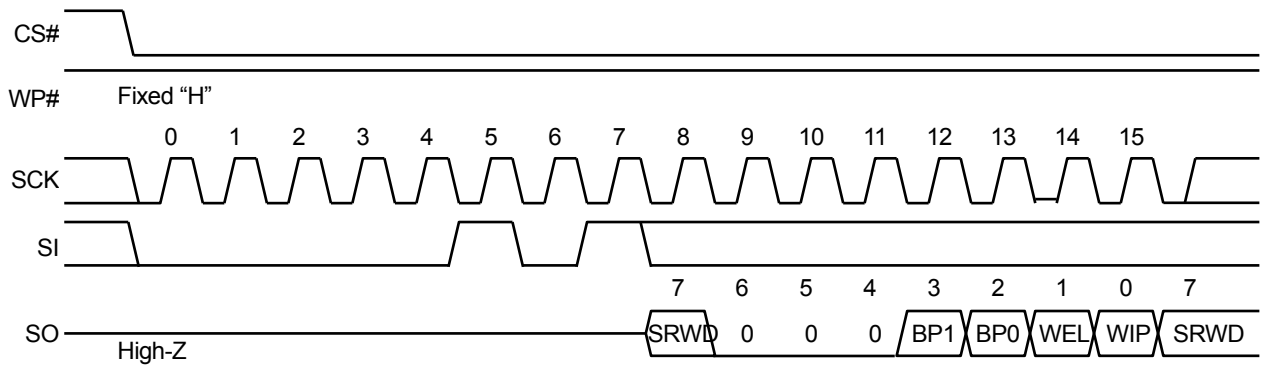
#### WRDI(Write Disable)

WRDI command resets WEL bit.



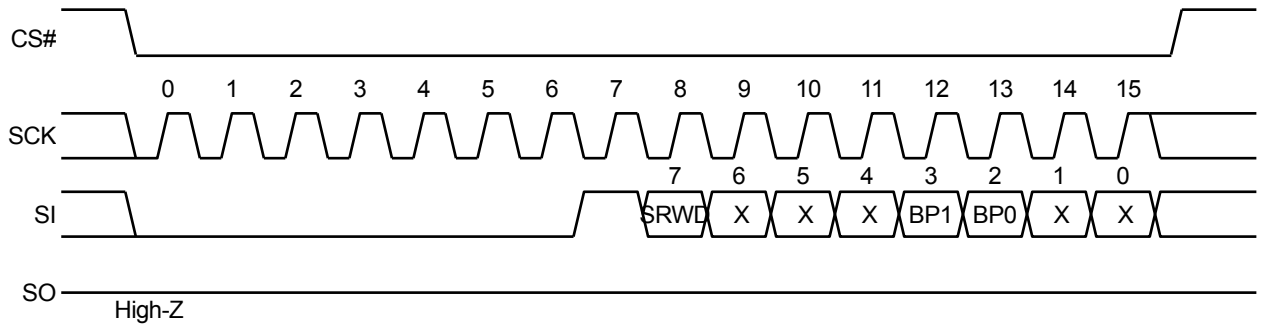
**RDSR(READ Status Register)**

The RDSR command allows to read data of status register.



**WRSR(WRITE Status Register)**

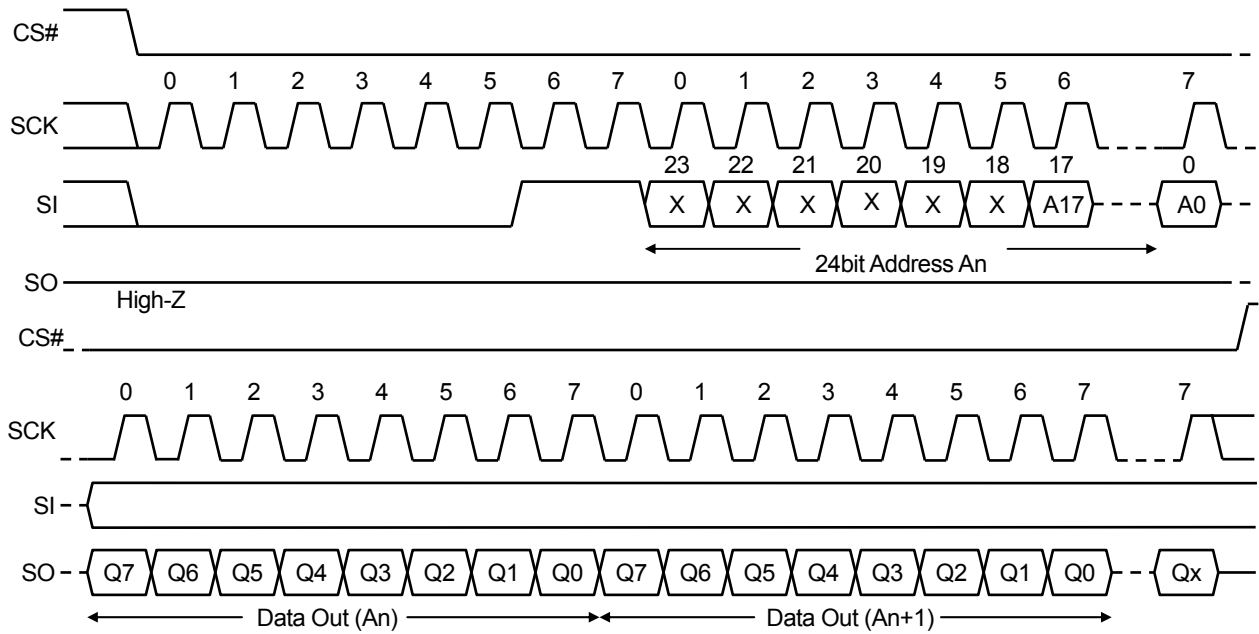
WRSR command allows to write data to status register(SRWD,BP0,BP1). It is necessary to set Write Enable Latch (WEL) bit by WREN command before executing WRSR.



Note:  
WP# = Fix "H"

**READ(Read from Memory Array)**

READ command can be valid when CS# goes “L”, then the op-code and 16bit-addresses are inputted to serial input “SI”. The inputted addresses are loaded to internal register, then the data from corresponded address is output at serial-output “SO”. If CS# will keep “L”, the internal address will be increased automatically after 8 clocks and will output the data from new-address. When it reaches the most significant address, the address counter rolls over to starting address, and reading cycle can be continued infinitely.

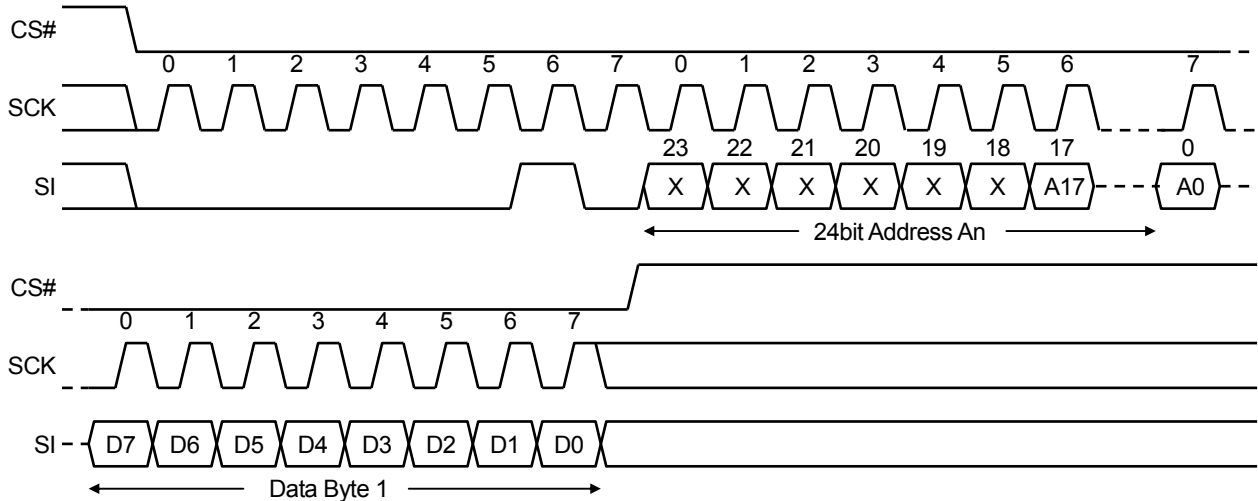


Note : WP# = fixed "H"

**WRITE(Write to Memory Array)**

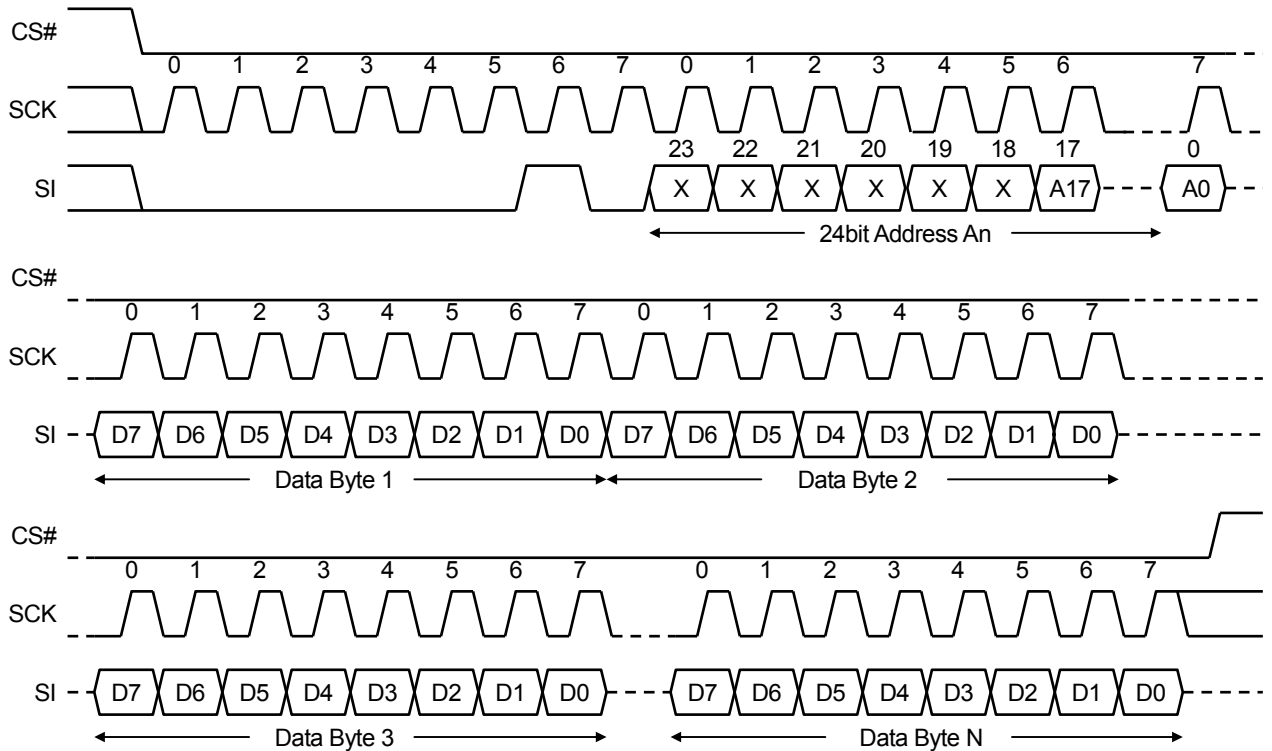
Write command can be valid when CS# goes “L”, then the op-code and 16bit-addresses are inputted to serial input “SI”. Writing is terminated when CS# goes high after data-input. If CS# will keep “L”, the internal address will be increased automatically. When it reaches the most significant address, the address counter rolls over to starting address 0000h, and writing cycle (overwriting) can be continued infinitely.

**WRITE(1Byte)**



Note : WP# = Fixed "H" , SO=High-Z

**WRITE(Page)**



Note : WP# = Fixed "H" , SO=High-Z

**Write Protection**

Writing protection block is shown as follows:

Protect Block size

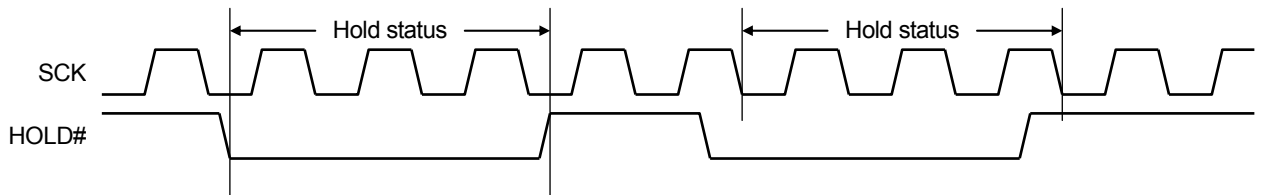
Block Protect BIT		Protected Block	Protected Address Area
BP1	BP0		
0	0	None	None
0	1	Upper 1/4 block	30000h – 3FFFFh
1	0	Upper 1/2 block	20000h – 3FFFFh
1	1	All	00000h – 3FFFFh

Writing Protect

WP#	SRWD	mode	Writing protection status in status register	Protection status in memory	
				Protected blocks	Unprotected blocks
1	0	Software protection (SPM)	Status register is unprotected when WEL-bit is set by WREN command. BP0 and BP1 are unprotected.	Protected	Unprotected
0	0				
1	1				
0	1	Hardware protection (HPM)	Status register is protected. BP0 and BP1 are protected.	Protected	Unprotected

**HOLD**

Hold status is used for suspending serial communication without disable the chip. SO becomes “High-Z” and SI is “Don’t care” during the hold status. It is necessary to keep CS#=L in hold status.





## ELECTRICAL CHARACTERISTICS

### Absolute Maximum Ratings

The application of stress (voltage, current, or temperature) that exceeds the absolute maximum rating may damage the device. Therefore, do not allow actual characteristics to exceed any one parameter ratings

### Pin voltages

Parameter	Symbol	Rating		Unit
		Min.	Max.	
Pin Voltage (Input Signal)	$V_{IN}$	-0.5	$V_{CC} + 0.5$	V
Pin Voltage (Input/Output Voltage)	$V_{INQ}, V_{OUTQ}$	-0.5	$V_{CC} + 0.5$	V
Power Supply Voltage	$V_{CC}$	-0.5	4.0	V

### Temperature Range

Parameter	Symbol	Rating		Unit	Note
		Min.	Max.		
Storage Temperature (Extended Temperature Version)	Tstg	-55	125	°C	
Operating Temperature (Extended Temperature Version)	Topr	-40	85	°C	

### Others

Parameter	Symbol	Rating	Unit
Power Dissipation	$P_D$	1,000mW	
Allowable Input Current	$I_{IN}$	+/- 20mA	Ta=25°C
Allowable Output Current	$I_{OUT}$	+/- 20mA	Ta=25°C

## Recommended Operating Conditions

### Power Supply Voltage

[V]

Parameter	Symbol	Min.	Typ.	Max.	Note
Power Supply Voltage	$V_{CC}$	2.7	3.3	3.6	
Ground Voltage	$V_{SS}$	0	0	0	

### DC Input Voltage

[V]

Parameter	Symbol	Min.	Max.	Note
Input High Voltage	$V_{IH}$	$V_{CC} \times 0.8$	$V_{CC} + 0.3$	
Input Low Voltage	$V_{IL}$	-0.3	$V_{CC} \times 0.15$	

## DC Characteristics

### DC Input/Output Characteristics

Parameter	Symbol	Condition	Min.	Max.	Unit	Note
Output High Voltage	$V_{OH}$	$I_{OH} = -2\text{mA}$	$V_{CC} \times 0.85$	—	V	
Output Low Voltage	$V_{OL}$	$I_{OL} = 2\text{mA}$	—	$V_{CC} \times 0.15$	V	
Input Leakage Current	$I_{LI}$	—	-10	10	$\mu\text{A}$	
Output Leakage Current	$I_{LO}$	—	-10	10	$\mu\text{A}$	

### Power Supply Current

$V_{CC} = \text{Max. to Min.}, T_a = T_{opr}$

Parameter	Symbol	Condition	Min.	Max.	Unit	Note
Power Supply Current (Standby)	$I_{CCS}$	$CS\# = V_{CC}, V_{IN} = 0\text{V or } V_{CC}$	—	100	$\mu\text{A}$	
Power Supply Current (Operating)	$I_{CCA}$	$V_{IN} = 0.2\text{V or } V_{CC} - 0.2\text{V}, SCK = \text{Max.}, I_{OUT} = 0\text{mA}$	—	10	mA	1

Note1: average current.

**AC Characteristics (Read Cycle)**

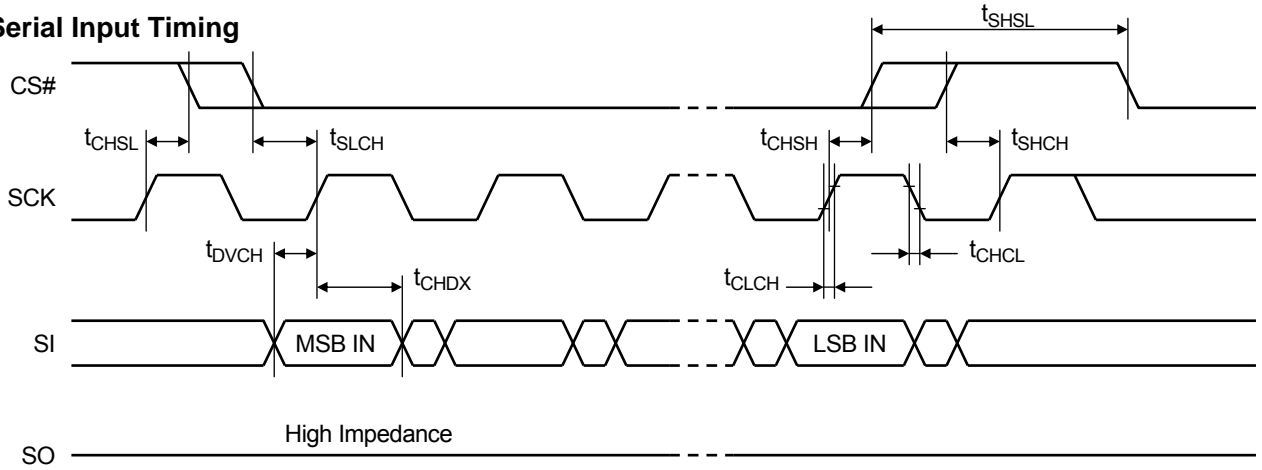
$V_{CC}$ =Max. to Min.,  $T_a$ =Topr.

Parameter	Symbol	MR45V200A		Unit	Note
		Min.	Max.		
Clock frequency	$f_C$	D.C.	34	MHz	
CS# Active setup time	$t_{SLCH}$	10	—	ns	
CS# In-active setup-time	$t_{SHCH}$	10	—	ns	
CS# De-select time	$t_{SHSL}$	10	—	ns	
CS# Active hold time	$t_{CHSH}$	10	—	ns	
CS# In-active hold-time	$t_{CHSL}$	10	—	ns	
SCK High time	$t_{CH}$	13	—	ns	1
SCK Low time	$t_{CL}$	13	—	ns	1
SCK Rise time	$t_{CLCH}$	—	50	ns	2
SCK Fall time	$t_{CHCL}$	—	50	ns	2
Data Setup time	$t_{DVCH}$	5	—	ns	
Data Hold time	$t_{CHDX}$	5	—	ns	
SCK Low Hold time after HOLD# inactive	$t_{HHCH}$	10	—	ns	
SCK Low Hold time after HOLD# active	$t_{HLCH}$	10	—	ns	
SCK High Setup time before HOLD# active	$t_{CHHL}$	10	—	ns	
SCK High Setup time before HOLD# inactive	$t_{CHHH}$	10	—	ns	
Output disable time	$t_{SHQZ}$	—	12	ns	2
SCK Low to Output Valid time	$t_{CLQV}$	—	12	ns	
Output Hold time	$t_{CLQX}$	0	—	ns	
HOLD# High to Output Low impedance time	$t_{HHQX}$	—	20	ns	2
HOLD# High to Output High impedance time	$t_{HLQZ}$	—	20	ns	2

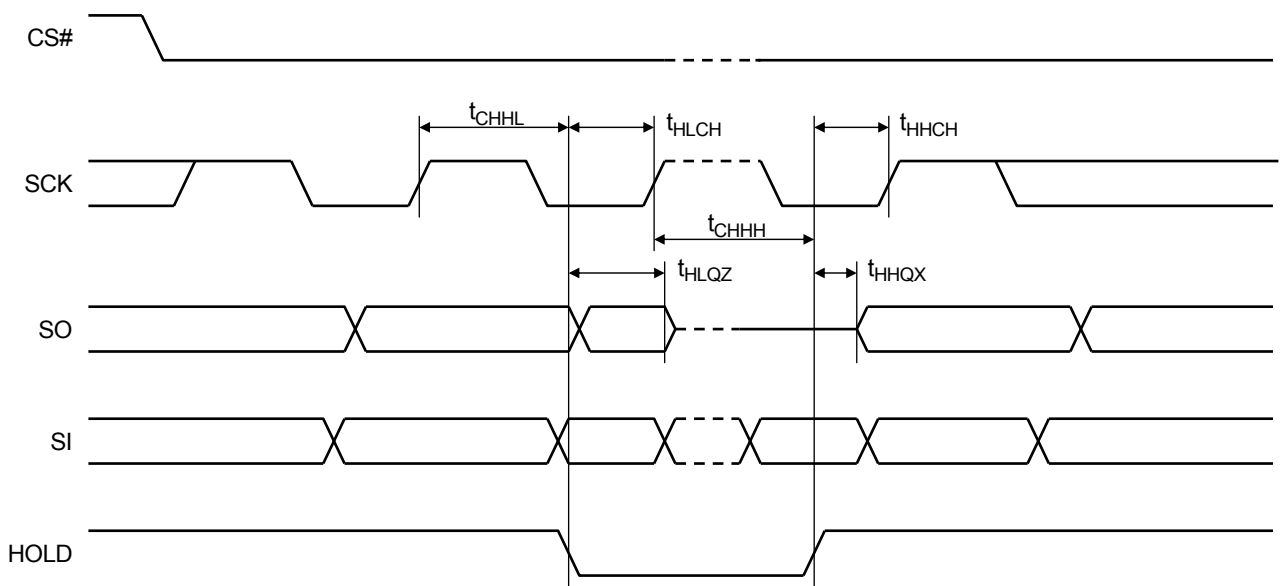
Note: 1.  $t_{CH} + t_{CL} \geq 1/f_C$   
2. sample value

**Timing Diagrams**

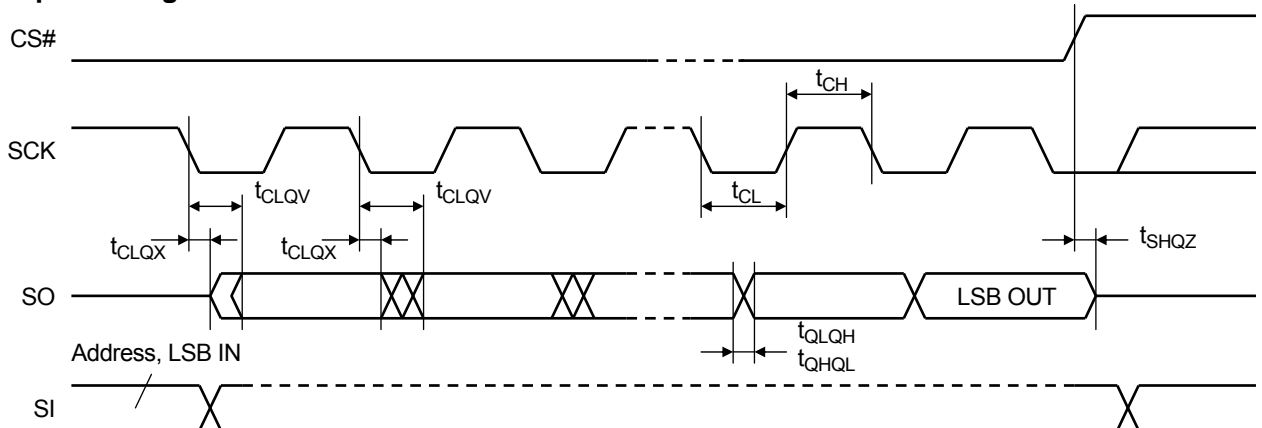
**Serial Input Timing**



**Hold Timing**



**Output Timing**



**•Power-On and Power-Off Characteristics**

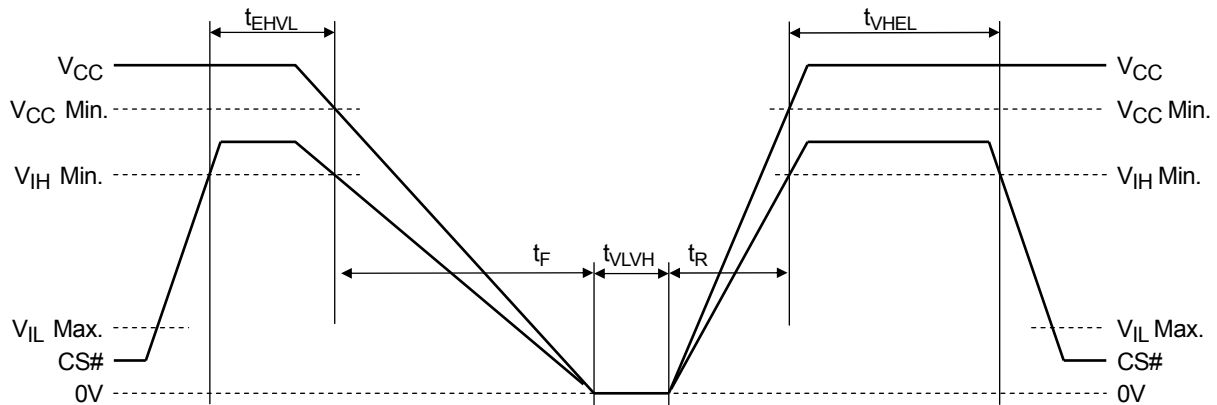
(Under recommended operating conditions)

Parameter	Symbol	Min.	Max.	Unit	Note
Power-On CS# High Hold Time	$t_{VHEL}$	50	—	$\mu\text{s}$	1, 2
Power-Off CS# High Hold Time	$t_{EHVL}$	100	—	ns	1
Power-On Interval Time	$t_{VLVH}$	1	—	$\mu\text{s}$	2
Power-On Rise time	$t_R$	50	100,000	$\mu\text{s/V}$	
Power-down Fall time	$t_F$	100		$\mu\text{s/V}$	

Notes:

1. To prevent an erroneous operation, be sure to maintain CS#="H", and set the FeRAM in an inactive state (standby mode) before and after power-on and power-off.
2. Powering on at the intermediate voltage level will cause an erroneous operation; thus, be sure to power up from 0 V.
3. Enter all signals at the same time as power-on or enter all signals after power-on.

**•Power-On and Power-Off Sequences**



**Read/Write Cycles and Data Retention**

(Under recommended operating conditions)

Parameter	Min.	Max.	Unit	Note
Read/Write Cycle	10 <sup>12</sup>	—	Cycle	
Data Retention	10	—	Year	

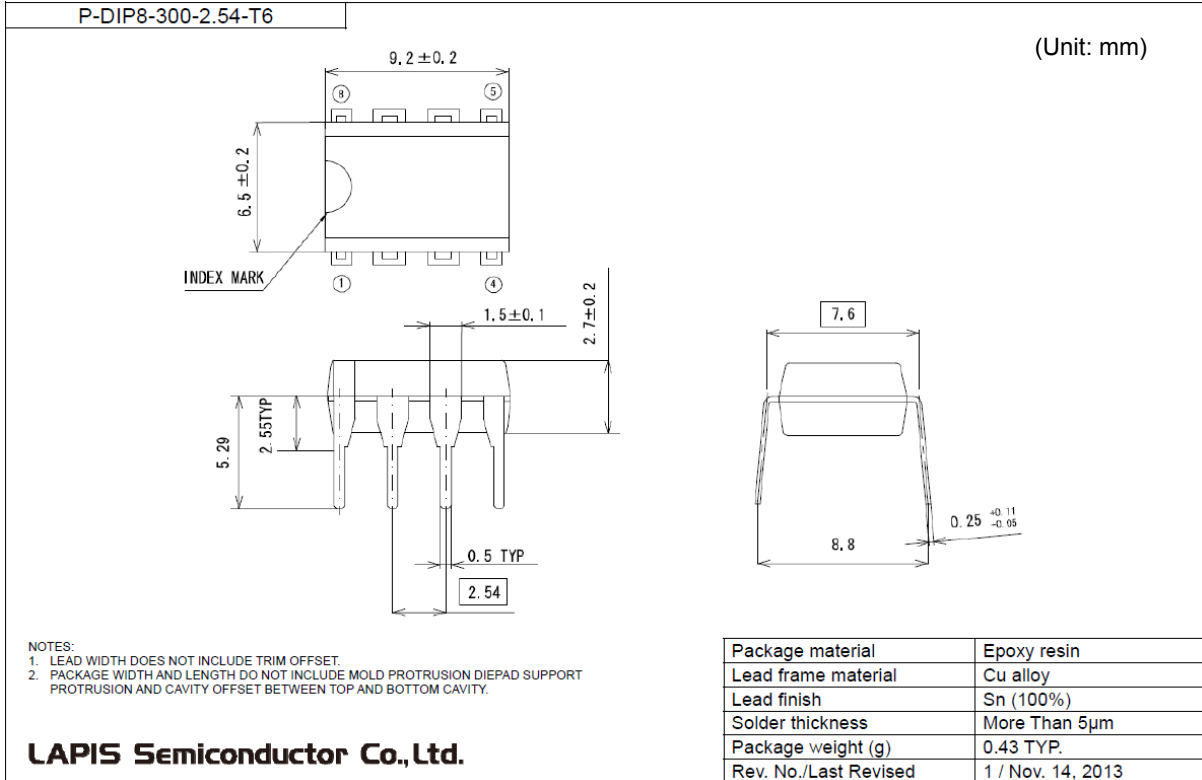
**Capacitance**

Signal	Symbol	Min.	Max.	Unit	Note
Input Capacitance	C <sub>IN</sub>	—	10	pF	1
Input/Output Capacitance	C <sub>OUT</sub>	—	10	pF	1

Note:

Sampling value. Measurement conditions are V<sub>IN</sub> = V<sub>OUT</sub> = GND, V<sub>CC</sub>=3.3V, f = 1MHz, and Ta = 25°C

**PACKAGE DIMENSIONS**



**REVISION HISTORY**

Document No.	Date	Page		Description
		Previous Edition	Current Edition	
FEDR45V200A-01	Jan. 31, 2014	–	–	Final edition 1



NOTES

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